MOSFET - Symmetrical Dual N-Channel

60 V, 9 mΩ, 38 A

NTTFD9D0N06HL

General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

Features

Q1: N-Channel

- Max $r_{DS(on)} = 9.0 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$
- Max $r_{DS(on)}$ = 13 m Ω at V_{GS} = 4.5, I_D = 8.0 A

Q2: N-Channel

- Max $r_{DS(on)} = 9.0 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$
- Max $r_{DS(on)} = 13 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 8.0 \text{ A}$
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- RoHS Compliant

Typical Applications

- Computing
- Communications
- General Purpose Point of Load

PIN DESCRIPTION

Pin	Name	Description
1, 11, 12	GND (LSS)	Low Side Source
2	LSG	Low Side Gate
3, 4, 5, 6	V + (HSD)	High Side Drain
7	HSG	High Side Gate
8, 9, 10	SW	Switching Node, Low Side Drain

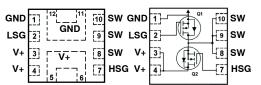


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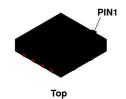
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
60 V	9 mΩ @ 10 V	38 A
	13 mΩ @ 4.5 V	36 A

ELECTRICAL CONNECTION



Dual N-Channel MOSFET





Bottom

WQFN12, 3x3 CASE 510CJ

MARKING DIAGRAM

&Z&3&K NTTFD 9D0N06HL

&Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

NTTFD9D0N06HL = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping†		
NTTFD9D0N06HLTWG	WQFN12 (Pb-Free)	3000 / Tape & Reel		

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$, Unless otherwise specified)

Symbol		Parameter		Q1	Q2	Units
V _{DS}	Drain-to-Source Voltage			60	60	V
V _{GS}	Gate-to-Source Voltage			±20	±20	V
I _D	Drain Current -Continuous	T _C = 25°C	(Note 4)	38	38	Α
	-Continuous	T _C = 100°C	(Note 4)	23	23	
	-Continuous	T _A = 25°C		9 (Note 1a)	9 (Note 1b)	
	-Pulsed	T _A = 25°C		349	349	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	46	46	mJ
P_{D}	Power Dissipation for Single Oper	ration $T_C = 25^{\circ}C$		26	26	W
	Power Dissipation for Single Oper	ration $T_A = 25^{\circ}C$		1.7 (Note 1a)	1.7 (Note 1b)	
T _J , T _{STG}	Operating and Storage Junction T	Operating and Storage Junction Temperature Range			+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	4.8	4.8	°C/W
$R_{\theta JA}$	R _{θJA} Thermal Resistance, Junction-to-Ambient (Note 1a), max copper 70 (Note 1a) 70 (Note 1b)			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1c), min copper	135 (Note 1a)	135 (Note 1b)	

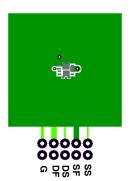
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
OFF CHAF	ACTERISTICS						
BV _{DSS}	Drain-to-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	60			V
		$I_D = 250 \mu A, V_{GS} = 0 V$	Q2	60			1
ΔBV_{DSS}	Breakdown Voltage Temperature	I _D = 250 μA, referenced to 25°C	Q1		37.38		mV/°C
ΔT_J	Coefficient	I _D = 250 μA, referenced to 25°C	Q2		37.38		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V	Q1			10	μΑ
		V _{DS} = 60 V, V _{GS} = 0 V	Q2			10	
I _{GSS}	Gate-to-Source Leakage Current,	$V_{GS} = +20/-16 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	nA
	Forward	V _{GS} = +20/-16 V, V _{DS} = 0 V	Q2			±100	1
ON CHAR	ACTERISTICS						
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 50 \mu A$	Q1	1.2	1.6	2.0	V
		$V_{GS} = V_{DS}, I_{D} = 50 \mu A$	Q2	1.2	1.6	2.0	1
$\Delta V_{GS(th)}$	Gate-to-Source Threshold Voltage	$I_D = 50 \mu A$, referenced to $25^{\circ}C$	Q1		-6.19		mV/°C
ΔT_{J}	Temperature Coefficient	I _D = 50 μA, referenced to 25°C	Q2		-6.19		1
r _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 10 A	Q1		7.3	9.0	mΩ
		V _{GS} = 4.5 V, I _D = 8 A			9.8	13	1
		V _{GS} = 10 V, I _D = 10 A, T _J = 125°C			12.7		1
r _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 10 A	Q2		7.3	9.0	mΩ
		V _{GS} = 4.5 V, I _D = 8 A			9.8	13	1
		V _{GS} = 10 V, I _D = 10 A, T _J = 125°C			12.7		1
9FS	Forward Transconductance	V _{DS} = 15 V, I _D = 10 A	Q1		53		S
		V _{DS} = 15 V, I _D = 10 A	Q2		53		1

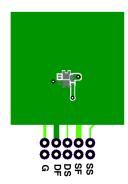
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
DYNAMIC	CHARACTERISTICS				•		
C _{ISS}	Input Capacitance	Q1:	Q1		948		pF
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ Mhz}$	Q2		948		
C _{OSS}	Output Capacitance	Q2:	Q1		188		pF
		V _{DS} = 30 V, V _{GS} = 0 V, f = 1 MHz	Q2		188		
C _{RSS}	Reverse Transfer Capacitance	1	Q1		12.3		pF
			Q2		12.3		1
R_{G}	Gate Resistance	T _A = 25°C	Q1		2.0		Ω
			Q2		2.0		
WITCHIN	IG CHARACTERISTICS						
td _(ON)	Turn-On Delay Time	Q1:	Q1		9.4		ns
		V_{DD} = 48 V, I_{D} = 19 A, V_{GS} = 4.5 V, R_{GEN} = 2.5 Ω	Q2		9.4		
t _r	Rise Time	Q2:	Q1		5.8		ns
		$V_{DD} = 48 \text{ V}, I_D = 19 \text{ A},$	Q2		5.8		
t _{D(OFF)} Turn-Off Delay Time	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 2.5 \Omega$	Q1		12.8		ns
			Q2		12.8		
t _f Fall Time	Fall Time		Q1		4.4		ns
			Q2		4.4		
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V	Q1		13.5		nC
			Q2		13.5		
Qg	Total Gate Charge	V _{GS} = 0 V to 4.5 V	Q1		6.4		nC
		Q1:	Q2		6.4		
Q_{gs}	Gate-to-Source Gate Charge	$V_{DD} = 48 \text{ V},$	Q1		2.6		nC
		I _D = 19 A Q2:	Q2		2.6		
Q_{gd}	Gate-to-Drain "Miller" Charge	$V_{DD} = 48 \text{ V},$	Q1		2.8		nC
		I _D = 19 A	Q2		2.8		
RAIN-SO	DURCE DIODE CHARACTERISTICS						
V _{SD} S	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 10 A (Note 2)	Q1		0.79	1.2	V
		V _{GS} = 0 V, I _S = 10 A (Note 2)	Q2		0.79	1.2	
t _{rr}	Reverse Recovery Time	Q1:	Q1		29		ns
		I _F = 19 A, di/dt = 100 A/μs Q2:	Q2		29		
Q_{rr}	Reverse Recovery Charge	I _F = 19 A, di/dt = 100 A/μs	Q1		14		nC
			Q2		14		

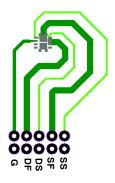
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
 R_{θJA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. R_{θCA} is determined by the user's board design.



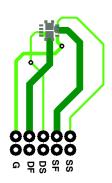
a) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



c) 135°C/W when mounted on a minimum pad of 2 oz copper.



d) 135°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μs , Duty cycle < 2.0%.
- Q1: E_{AS} of 46 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 9.6 A, V_{DD} = 60 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 9.6 A. Q2: E_{AS} of 46 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 9.6 A, V_{DD} = 60 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 9.6 A.
 Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal
- & electro-mechanical application board design.

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TYPICAL CHARACTERISTICS

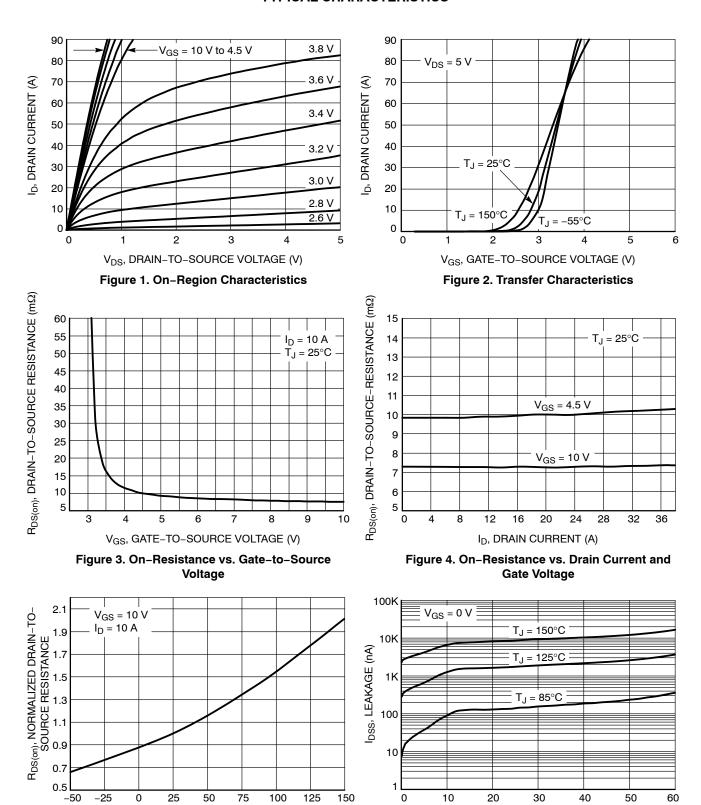


Figure 5. On–Resistance Variation with Temperature

T_J, JUNCTION TEMPERATURE (°C)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

TYPICAL CHARACTERISTICS

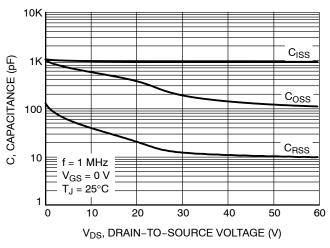


Figure 7. Capacitance Variation

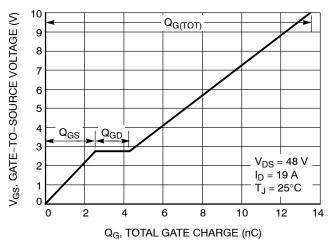


Figure 8. Gate-to-Source vs. Total Charge

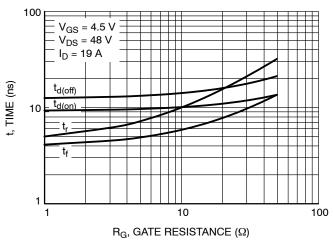


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

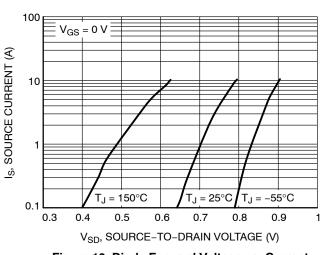


Figure 10. Diode Forward Voltage vs. Current

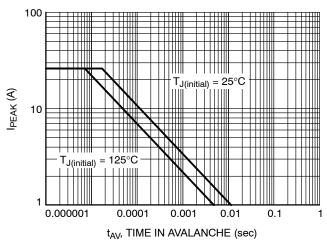


Figure 11. Unclamped Inductive Switching Capability

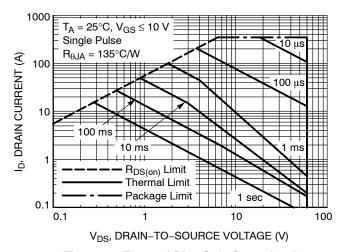


Figure 12. Forward Bias Safe Operating Area

TYPICAL CHARACTERISTICS

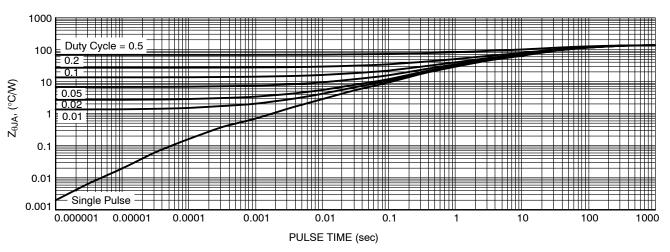
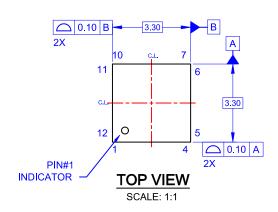
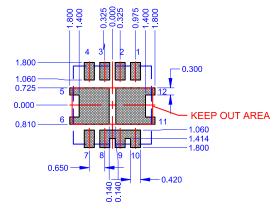


Figure 13. Transient Thermal Impedance

PACKAGE DIMENSIONS

WQFN12 3.3X3.3, 0.65PCASE 510CJ ISSUE O



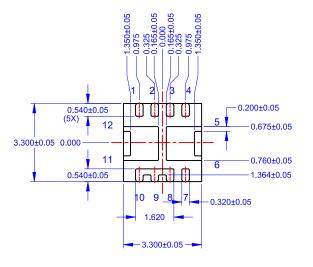


LAND PATTERN RECOMMENDATION

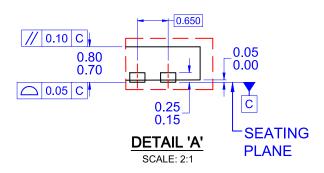
SCALE 1:1



FRONT VIEW SCALE: 1:1



BOTTOM VIEW SCALE: 1:1



NOTES: UNLESS OTHERWISE SPECIFIED

- A) DRAWING DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-220, VARIATION WEEC-1
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.

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